

Notice of References Cited	Application/Control No. 10/702,170		Applicant(s)/Patent Under Reexamination INOUE, HITOSHI	
	Examiner Steven Kau		Art Unit 2625	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-5,369,499	11-1994	Yip, Kwok-leung	358/406
*	C	US-6,044,204	03-2000	Takamatsu et al.	358/1.9
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	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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